

Precision Micropower Shunt Voltage Reference in bare die form

Rev 1.0 26/10/23

Description

The LM4040C-10 is a high precision, two-terminal shunt mode, bandgap voltage reference with fixed reverse breakdown voltage of 10V. The device is ideal for space-critical high reliability applications with initial 0.5% accuracy and 100ppm/°C max temperature coefficient. A 120µA to 15mA shunt current capability with low dynamic impedance ensures stable reverse breakdown voltage accuracy over a wide current range and operating temperature. No external stabilizing capacitors are required.

Ordering Information

The following part suffixes apply:

- No suffix MIL-STD-883 /2010B Visual Inspection
- "H" MIL-STD-883 /2010B Visual Inspection + MIL-PRF-38534 Class H LAT
- "K" MIL-STD-883 /2010A Visual Inspection (Space)
 + MIL-PRF-38534 Class K_AT

LAT = Lot Acceptance Test.

For further information on LAT process flows see below.

www.siliconsupplies.com\quality\bare-die-lot-qualification

Supply Formats:

- Defact Die in Waffle Pack (400 per tray capacity)
- Sawn Wafer on Tape On request
- Unsawn Wafer On request
- Die Thickness <> 280µm(11 Mils) On request
- In Metal or Ceramic package On request

Features:

- ±0.5% (max) output voltage tolerance at 25°C
- 20ppm/°C typical temperature coefficient at 25°C
- Wide operating current range 12 µA to 15mA
- No output capacitor required
- Tolerates capacitive load
- Bandgap reference corrects temperature drift
- Specified over mutary temperature range.

Die Dinensions in µm (mils)



Mechanical Specification

800 x 800	μm		
31.5 x 31.5	mils		
90 x 90	μm		
3.54 x 3.54	mils		
260 (±20)	μm		
10.24 (±0.8)	mils		
Al 1%Si 1.4µm			
Ti/Ni/Ag 1.2µm			
	31.5 x 31.5 90 x 90 3.54 x 3.54 260 (±20) 10.24 (±0.8) Al 1%Si 1.4µ		







$$R_{\rm S} = \frac{V_{\rm S} - V_{\rm R}}{I_{\rm L} + I_{\rm R}}$$





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Absolute Maximum Ratings¹ $T_A = 25^{\circ}C$ unless otherwise stated

PARAMETER	SYMBOL	VALUE	UNIZ		
Reverse Current	I _R	25	nΑ		
Forward Current	I _F	10	n.A.		
Operating Temperature Range	TJ	-55 to 150	С		
Storage Temperature	T _{STG}	-65 to 150	°C		

1. Operation above the absolute maximum rating may cause device failure. Operation at the absolute maximum ratings, to extended periods, may reduce device reliability.

Recommended Operating Conditions T_J = 25°C unless otherwise stated

SYMBOL	MIN	MAX	UNIT
I _R	0.12	15	mA
	-55 tc	55 to 125	
		0.12	I _R 0. 2 15

Electrical Characteristics, T_J = 25°C unless otherwise stated

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Reverse Breakdown Voltage	V _R	I _R =150μχ	-	10	-	V
	- //	I _R =150μΑ	-	-	±50	mV
Reverse Breakdown Voltage Tolerance ²		I _R =150μA, T _J = -40 to 85°C	-	-	±115	
J.		I _R =1500A ·T _J = -55 to 125°C	-	-	±135	
		T _J = 25°C	-	75	120	μΑ
Minimum Operating Current	I _{RMIN}	T _J = -40 to 85°C	-	-	125	
Guirein		T _J = -55 to 125°C	-	-	145	
		I _R =10mA	-	±40	-	ppm /°C
Average Reverse Breakdown Voltage	ΔV _R / ΔΤ	I _R =1mA	-	±20	-	
		I _R =150μA	-	±20	-	
Temperature Coefficient ²		I _R =10mA, T _J = -55 to 125°C	-	-	±100	
		I _R =1mA, T _J = -55 to 125°C	-	-	±100	
		$I_R = 150 \mu A, T_J = -55 \text{ to } 125^{\circ}\text{C}$	-	-	±100	
Breakdown Voltage Change with Operating Current Change ⁷	ge with $\Delta V_R / \Delta I_R$	$I_{\rm RMIN} \le I_{\rm R} \le 1 {\rm mA}$	-	0.8	1.5	
		$I_{RMIN} \le I_R \le 1mA$, $T_J = -55$ to $125^{\circ}C$	-	-	3.5	mV
		1mA≤ I _R ≤ 15mA	-	8	14	
		$1mA \le I_R \le 15mA$, $T_J = -55$ to $125^{\circ}C$	-	-	24	





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Electrical Characteristics, T_J = 25°C unless otherwise stated

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	
Reverse Dynamic Impedance	Z _R	I_R = 1mA, f = 120 Hz, I_{AC} = 0.1 I_R	-	0.7	1.7	Ω
Wideband Noise	e _N	l _R =150µA, 10 Hz ≤ f ≤ 10 kHz	-	180		μV _{RMS}
Reverse Breakdown Voltage Long Term Stability	ΔV_R	t = 1000 hours T = 25°C ±0.1°C, I _R =100µA	-	122	-	ppm
Thermal Hysteresis	V _{HYST}	ΔT = -40 to 125°C	Ci	0.08	-	%

2. Reverse Breakdown Tolerance is defined as the room temperature Reverse Breakdown Votage Jolerance $\pm[(\Delta V_R/\Delta T)(max\Delta T)(V_R)]$. Where, $\Delta V_R/\Delta T$ is the V_R temperature coefficient, max ΔT is the maximum difference in temperature from the reference point of 25°C to T_{MIN} or T_{MAX} , and V_R is the reverse breakdown voltage. 3. Load regulation is measured on pulse basis from no lo d to the specified load current. Output changes due to die temperature change must be taken into account separately. Thermal hysteresis is defined as the difference in voltage measured at +25°C after cycling to temperature -40°C and the 25°C measurement after cycling to temperature+125°C.

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